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## VI SEMESTER

MID SEMESTER EXAMINATION
B.Tech MARCH 2019

## EC310 Testing and diagnosis of digital system design

Time: 90 Minutes
Max. Marks : 25
Note : All questions carry equal marks,
Assume suitable missing data, if any
'All symbols and abbreviations have their usual meanings".
Q. 1 [i]A gate level fan-out free realization of a circuit has 20 inputs and 2 outputs. What is the minimum number of tests we will need to test this circuit?
[ii]lf a fault f 1 dominates fault f 2 , and the fault f 2 dominates a fault f3, which of these faults can be deleted to reduce the fault list for faưlt detection? Explain why.
[iii] Count the total number of possible single stuck at fault sites in Figure 1.


Figure 1
Q. 2 In Figure 2, use the PODEM algorithm to test for a SA1 on the output of gate 6 . Write on the figure and explain the sequence of decisigns.
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\begin{aligned}
& \text { Q. } 5 \text { In Figure 3, } \\
& \text { [i] Enumerate the minimal set of single stuck-at faillts that must } \\
& \text { be tested according to the Checkpoint Theorem. } \\
& \text { [ii] Show that the two faults } \mathrm{d} s-\mathrm{a}-0 \text { and } \mathrm{g} s-\mathrm{a}-1 \text { are equivalent. }
\end{aligned}
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